

Electrostatic Doping in Carbon-based Nanoelectronics Devices

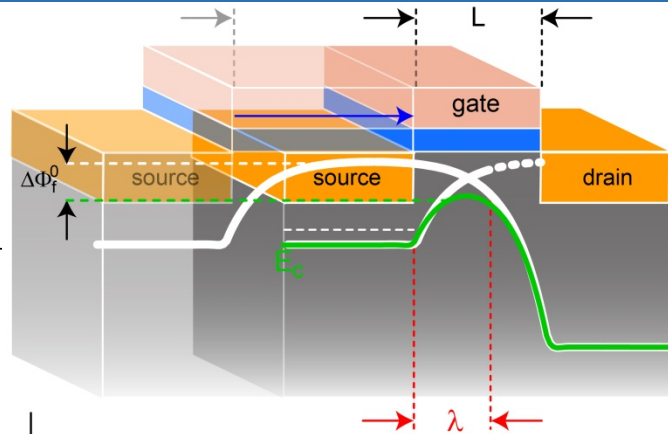
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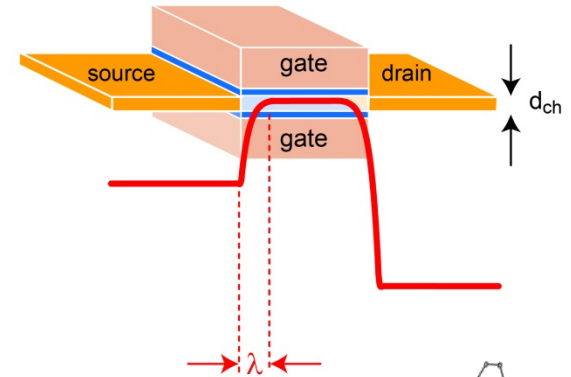
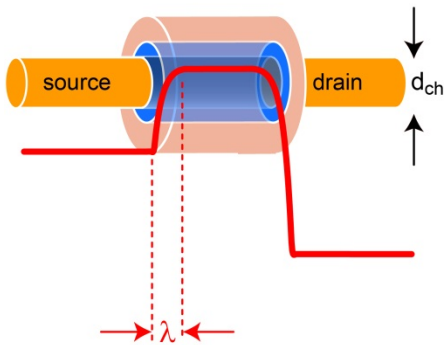


Introduction

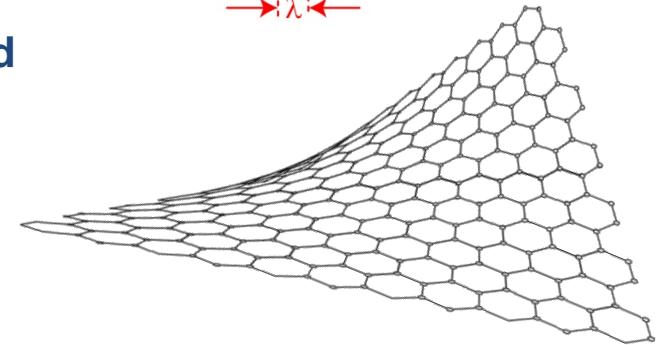
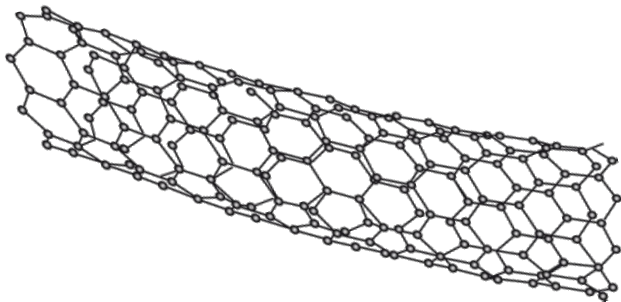
$$\lambda = \sqrt{\frac{\epsilon_{\text{nw}} d_{\text{nw}}^2}{8\epsilon_{\text{ox}}} \ln\left(1 + \frac{2d_{\text{ox}}}{d_{\text{nw}}}\right)}$$



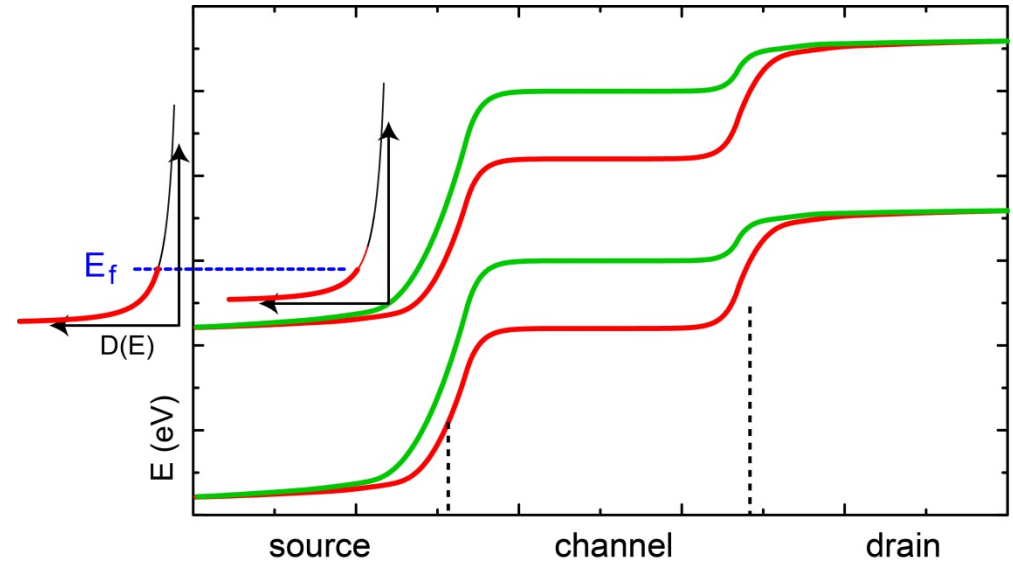
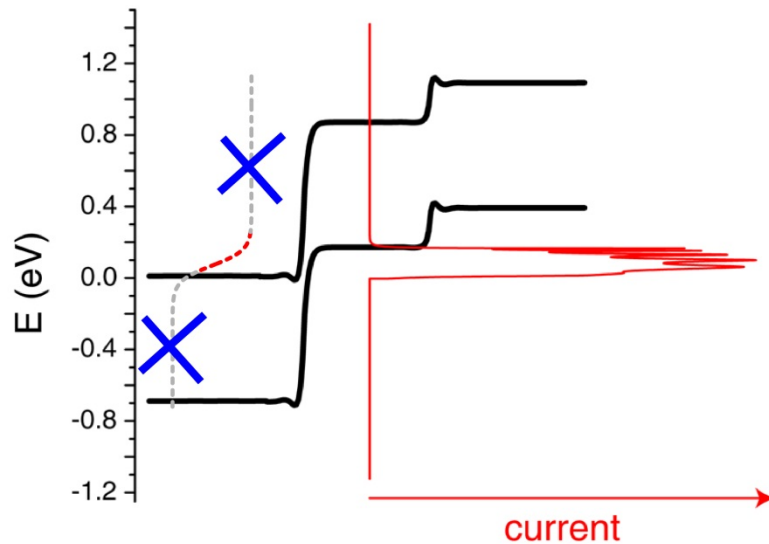
$$\lambda_{\text{ch}} = \sqrt{\frac{\epsilon_{\text{ch}}}{\epsilon_{\text{ox}}} d_{\text{ox}} d_{\text{ch}}}$$



**carbon-based materials
hold promise to realize
ultimate FETs due to
optimum scalability and
electronic transport
properties**



Introduction – Issues with Doping



- need excellent gate control of channel and screening of gate impact on source contact
- low density of states such as in carbon nanotubes (1D) or graphene detrimental for screening

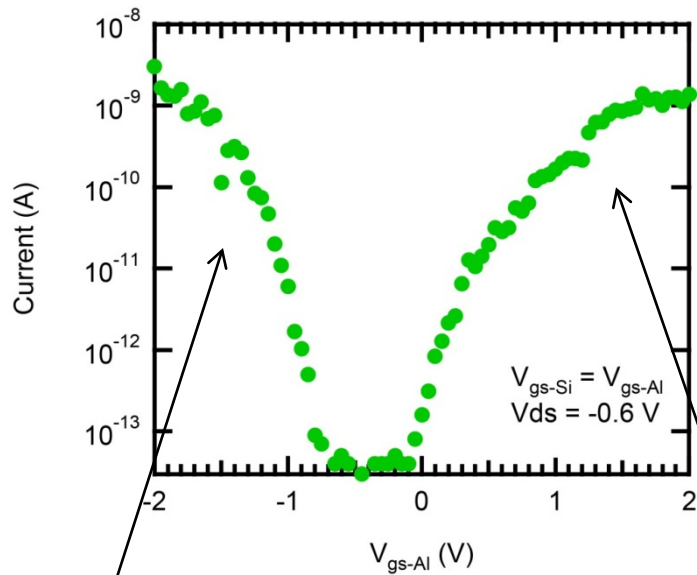


electrostatic doping

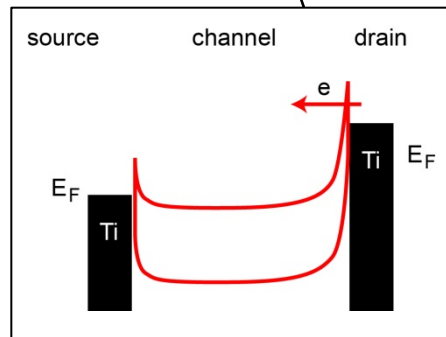
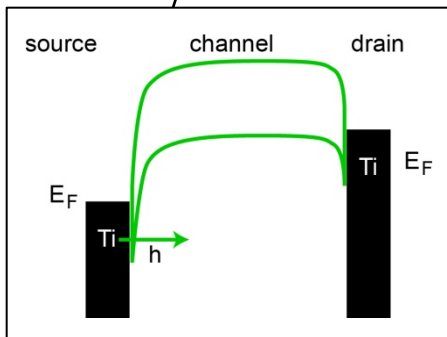
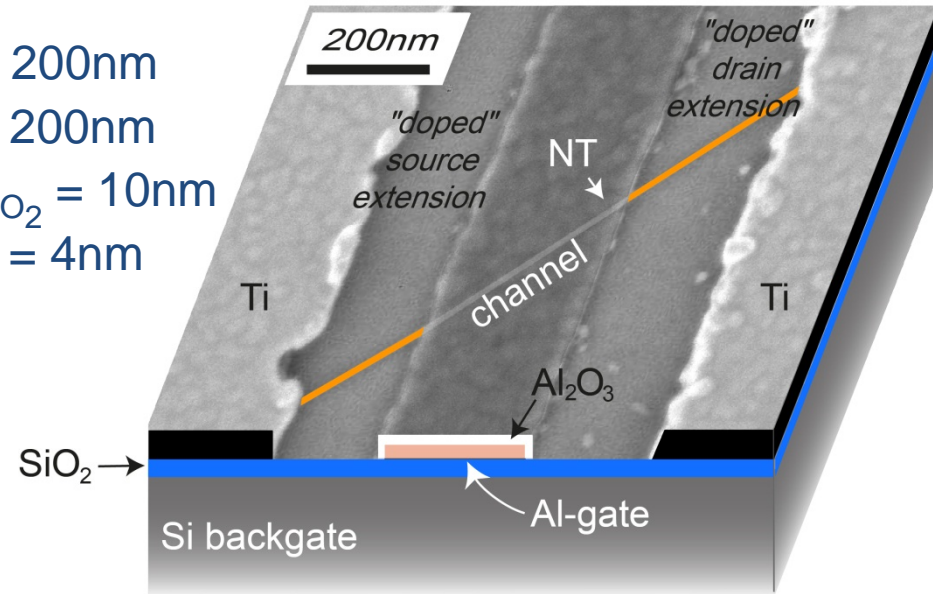
J. Knoch and J. Appenzeller, *phys. stat solidi a*, **205**, 679 (2008).

J. Knoch, S. Mantl and J. Appenzeller, *Solid-State Electron.*, **51**, 572 (2007).

Tunable Polarity in CNFETs



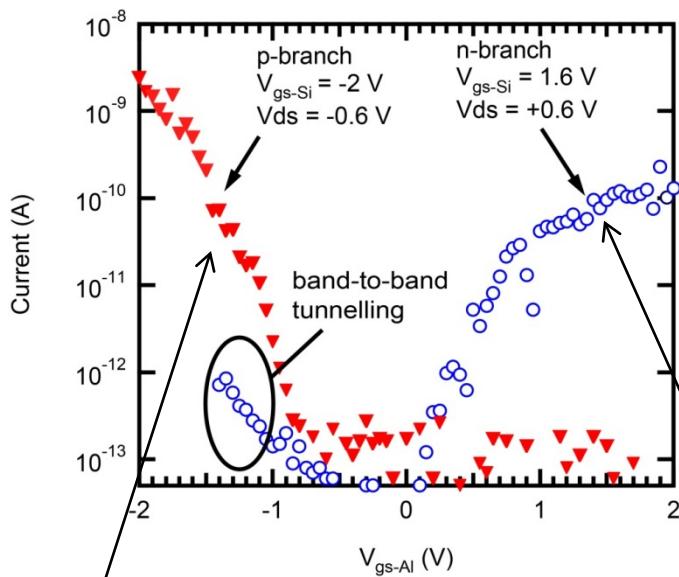
- $L_{bg} \approx 200 \text{ nm}$
- $L_{ch} \approx 200 \text{ nm}$
- $d_{ox-SiO_2} = 10 \text{ nm}$
- $d_{ox-Al} = 4 \text{ nm}$



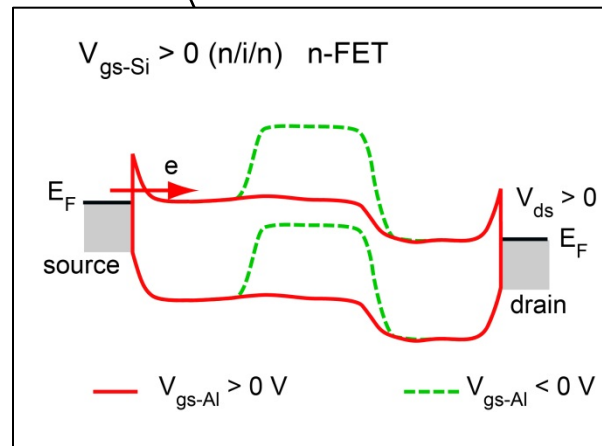
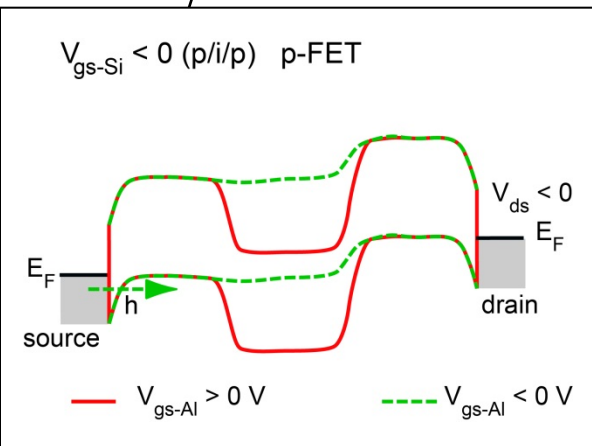
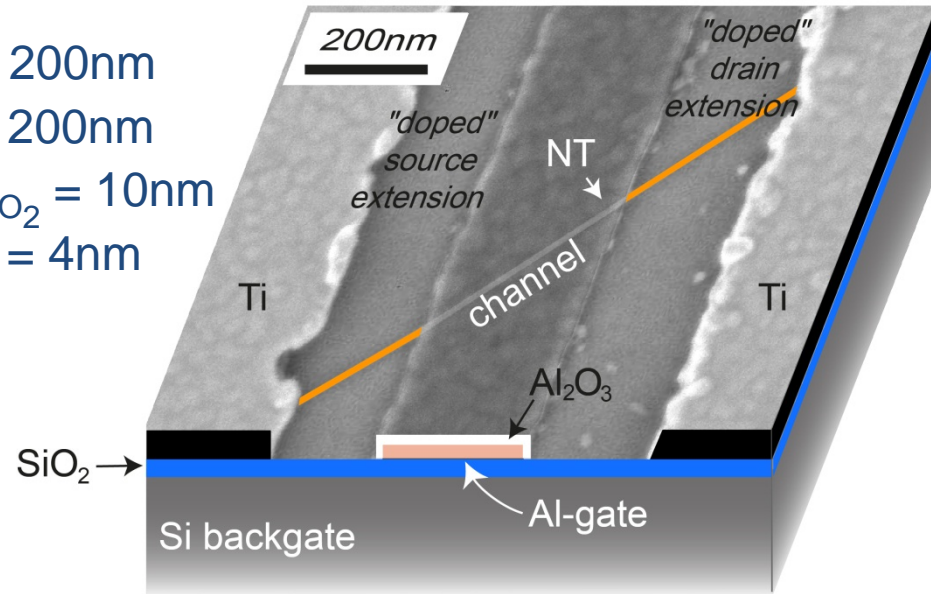
- ambipolar behavior if both gates biased in the same direction
- electron and hole injection through Schottky-barrier at Ti-nanotube interface

Y.-M. Lin, J. Appenzeller, J. Knoch and Ph. Avouris, IEEE Trans. Nanotechnol., 4, 481 (2005).

Tunable Polarity in CNFETs



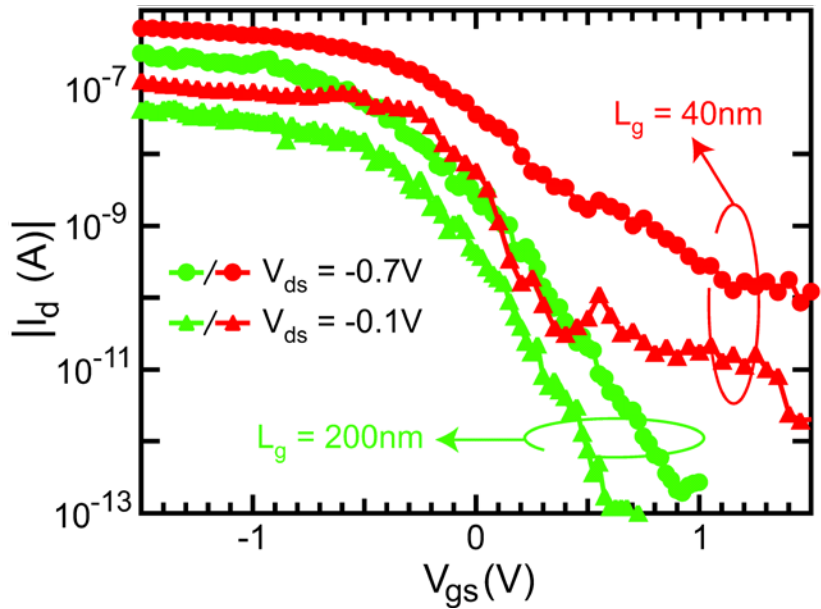
- $L_{bg} \approx 200$ nm
- $L_{ch} \approx 200$ nm
- $d_{ox-SiO_2} = 10$ nm
- $d_{ox-Al} = 4$ nm



- unipolar device behavior if both gates are biased with opposite polarity
- n- and p-type CNFETs possible due to excellent gate control

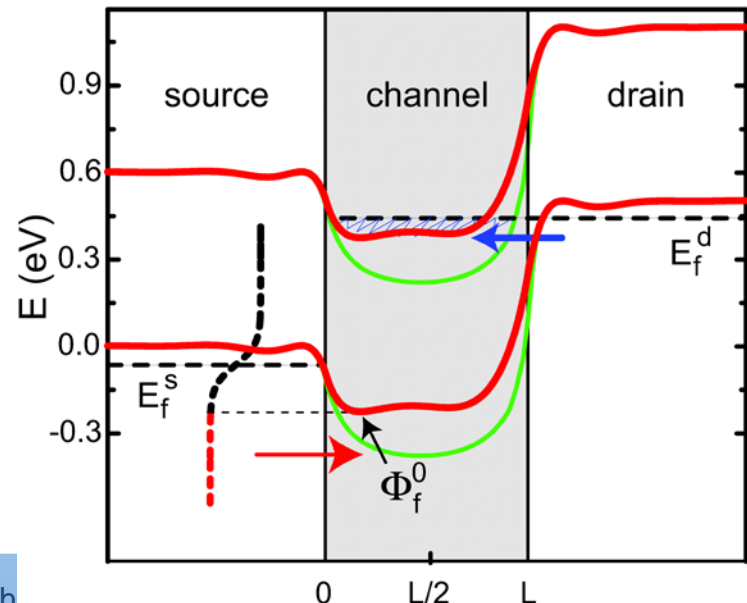
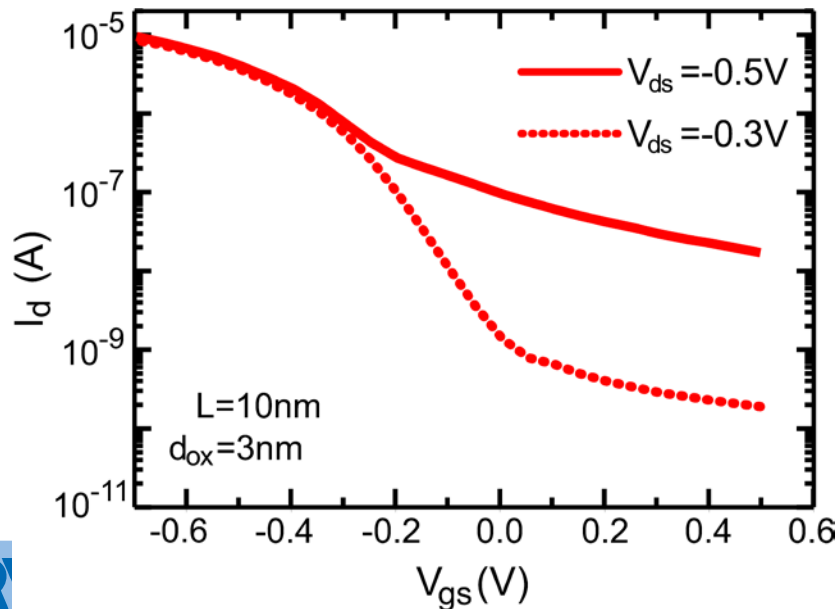
Y.-M. Lin, J. Appenzeller, J. Knoch and Ph. Avouris, IEEE Trans. Nanotechnol., 4, 481 (2005).

Conventional CNFETs

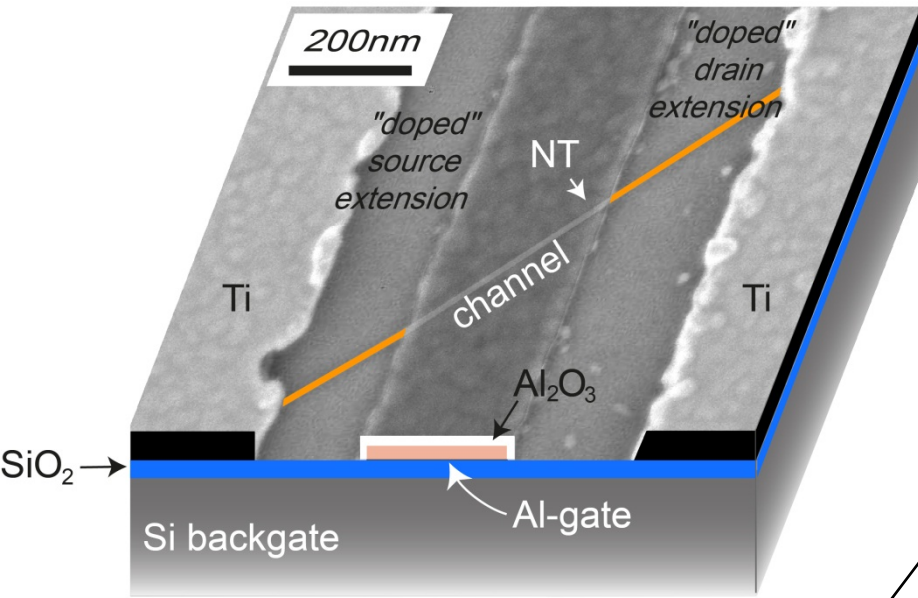


- device should be scalable to $L < 20\text{nm}$ without SCE
- increasing off-state leakage for short conventional CNFETs

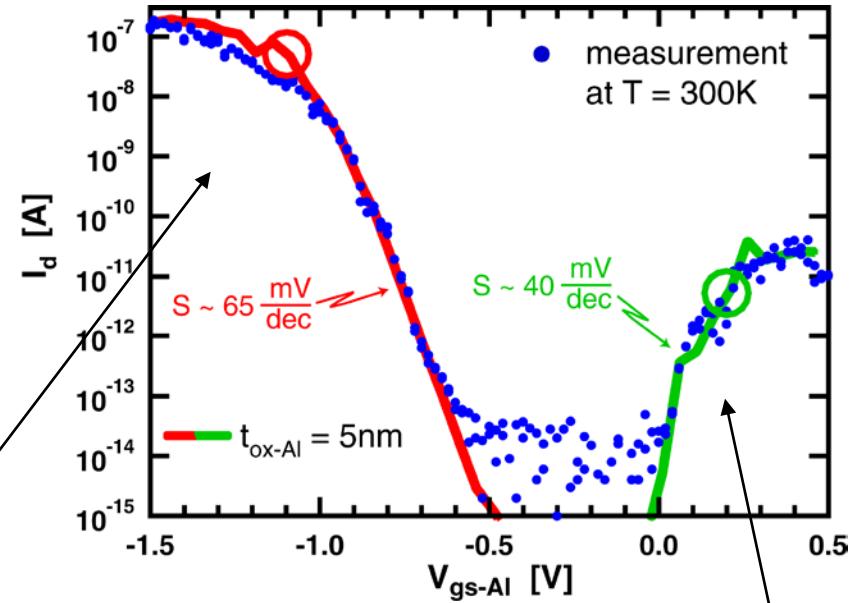
J. Knoch, S.Mantl and J. Appenzeller, Solid-State Electron., **49**, 73 (2005)



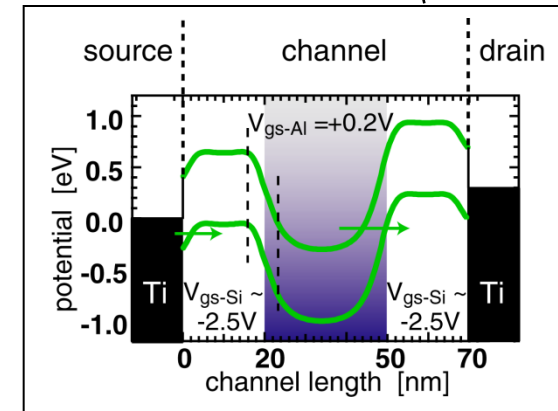
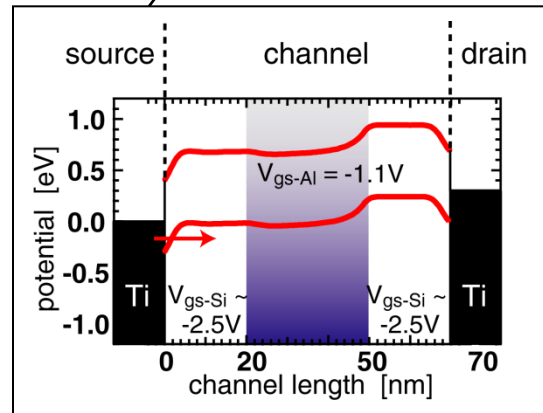
Tunnel-FET based on CNTs



$$d_{NT} \approx 1.4\text{nm} \quad d_{ox} = 4\text{nm}$$



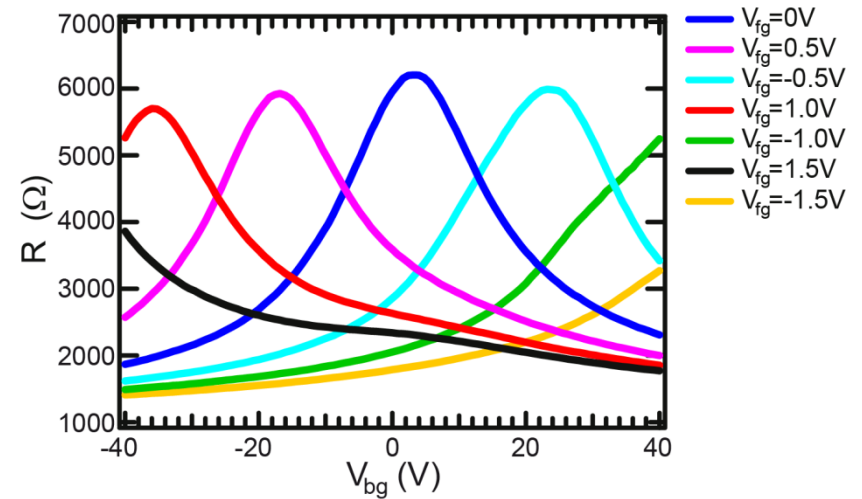
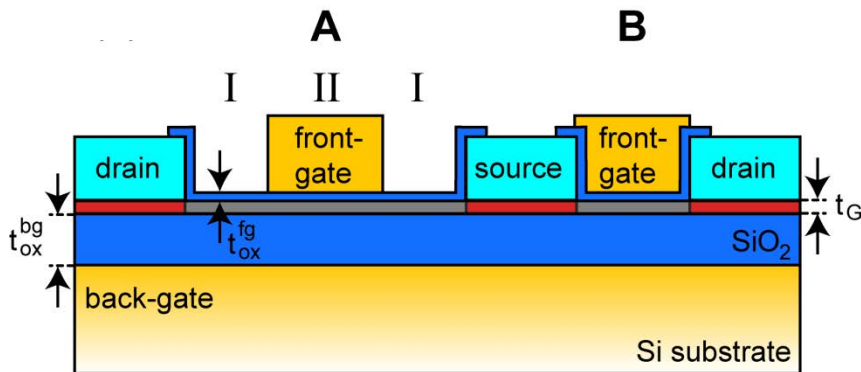
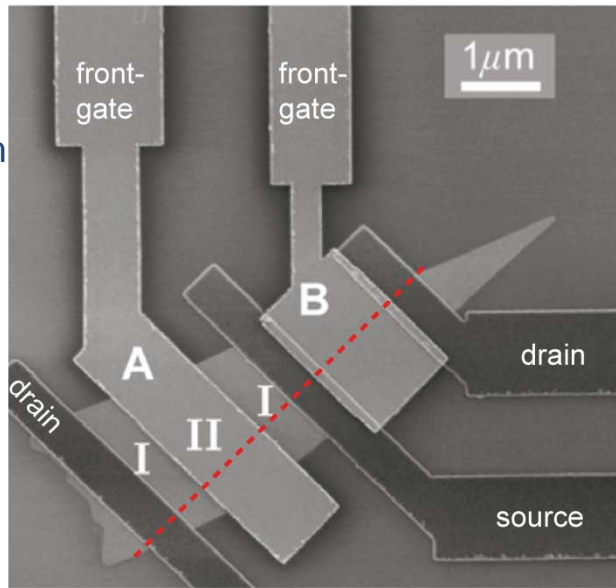
→ $S = 40\text{mV/dec}$



J. Appenzeller, Y.-M. Lin, J. Knoch, Z. Chen and Ph. Avouris, IEEE Trans. Electron Dev., **52**, 2568 (2005).

Electrostatic Doping in Graphene

$L=1\text{mm}$
 $W=1\text{mm}$
 $t_{\text{ox,bg}}=300\text{nm}$
 $t_{\text{ox,fg}}=10\text{nm}$
 Pd contacts

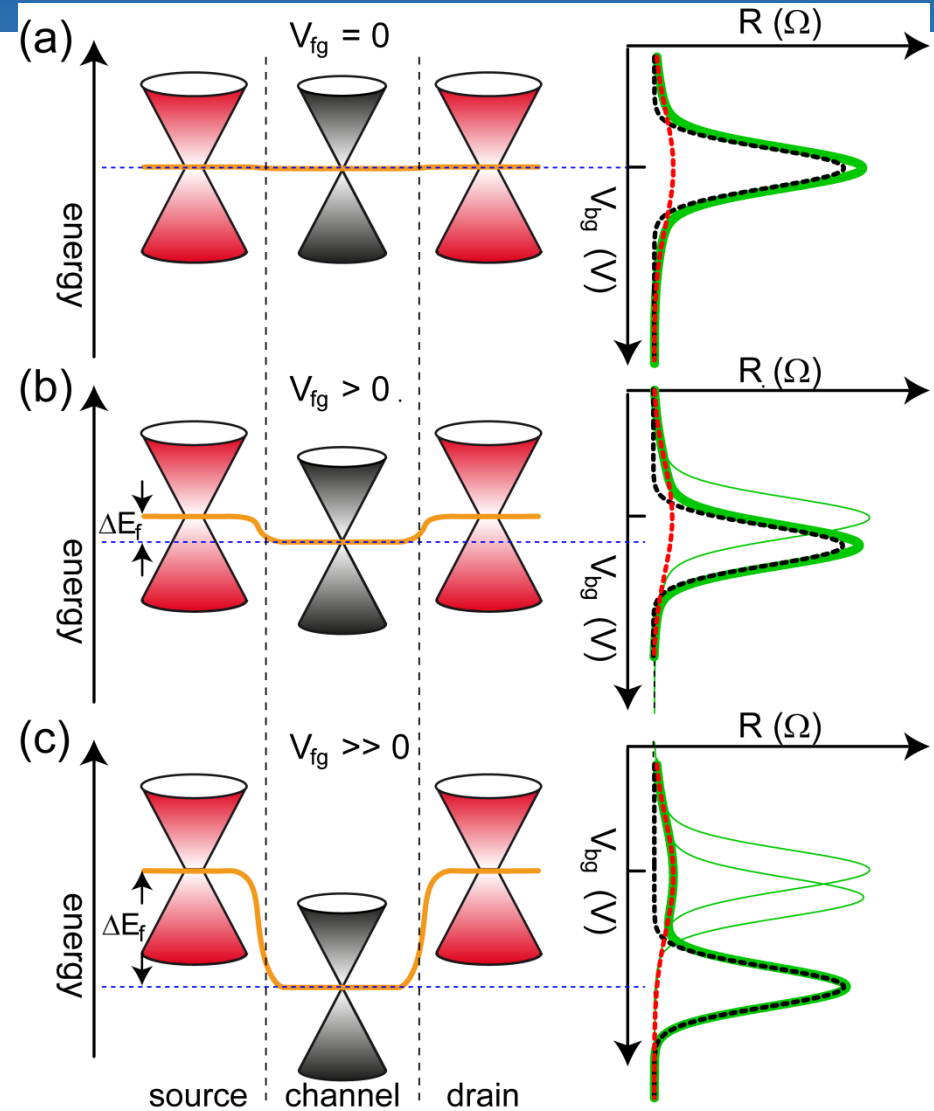
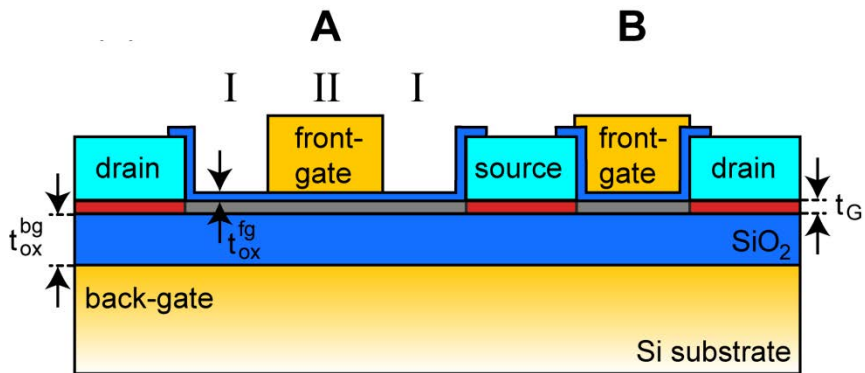
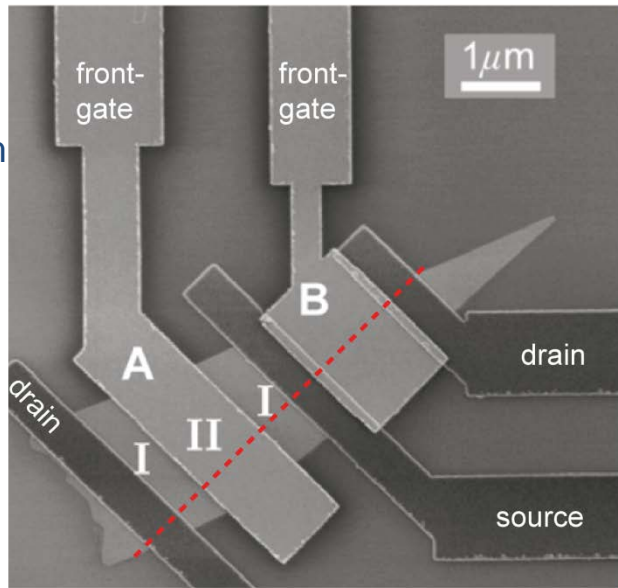


- back-gate characteristics of device „B“ show double peak-structure
- second peak much less pronounced than main peak

J. Knoch, Z. Chen and J. Appenzeller, IEEE Trans. Nanotechnol., **11**, 513 (2012).

Electrostatic Doping in Graphene

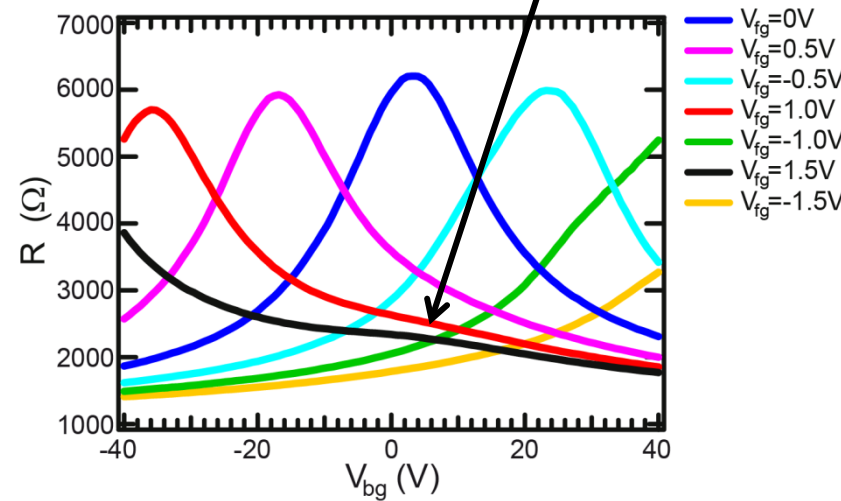
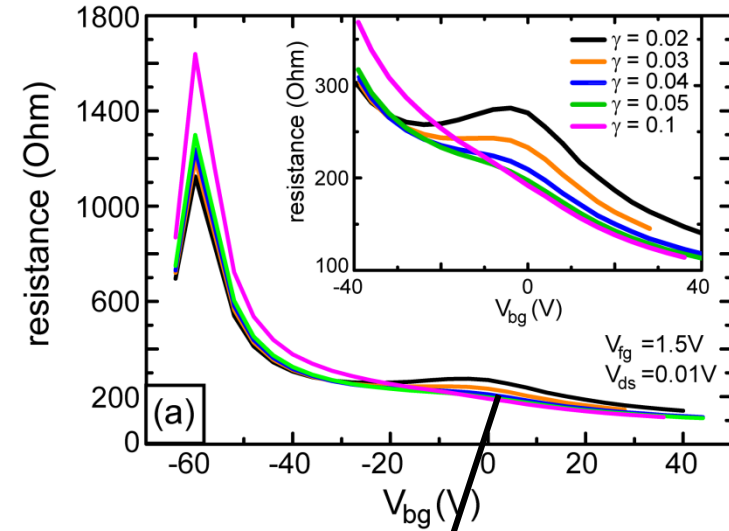
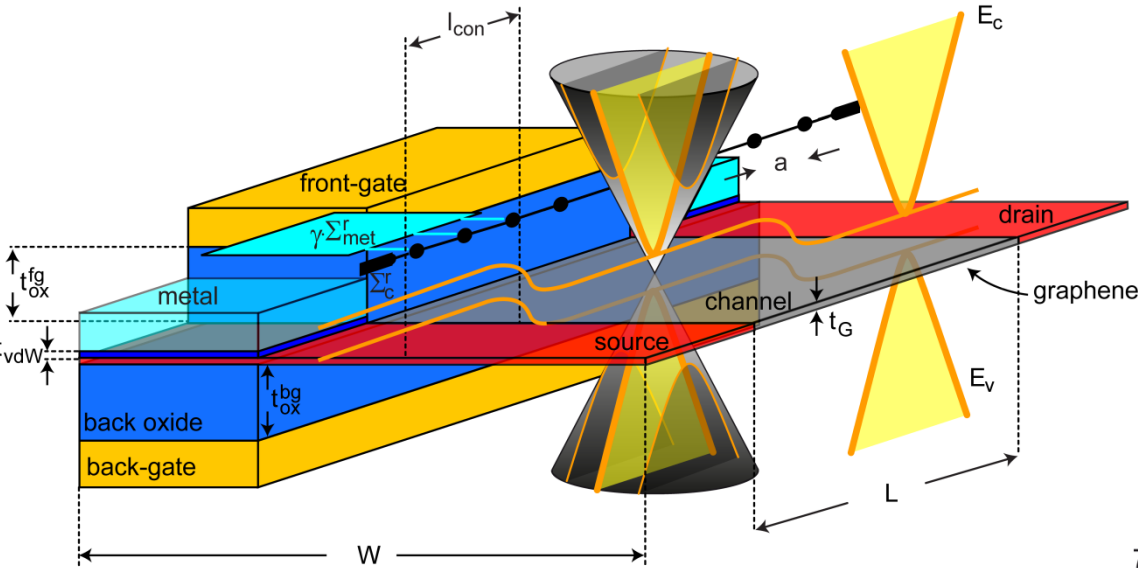
$L=1\text{mm}$
 $W=1\text{mm}$
 $t_{\text{ox,bg}}=300\text{nm}$
 $t_{\text{ox,fg}}=10\text{nm}$
 Pd contacts



- **second peak observable**

J. Knoch, Z. Chen and J. Appenzeller, IEEE Trans. Nanotechnol., **11**, 513 (2012).

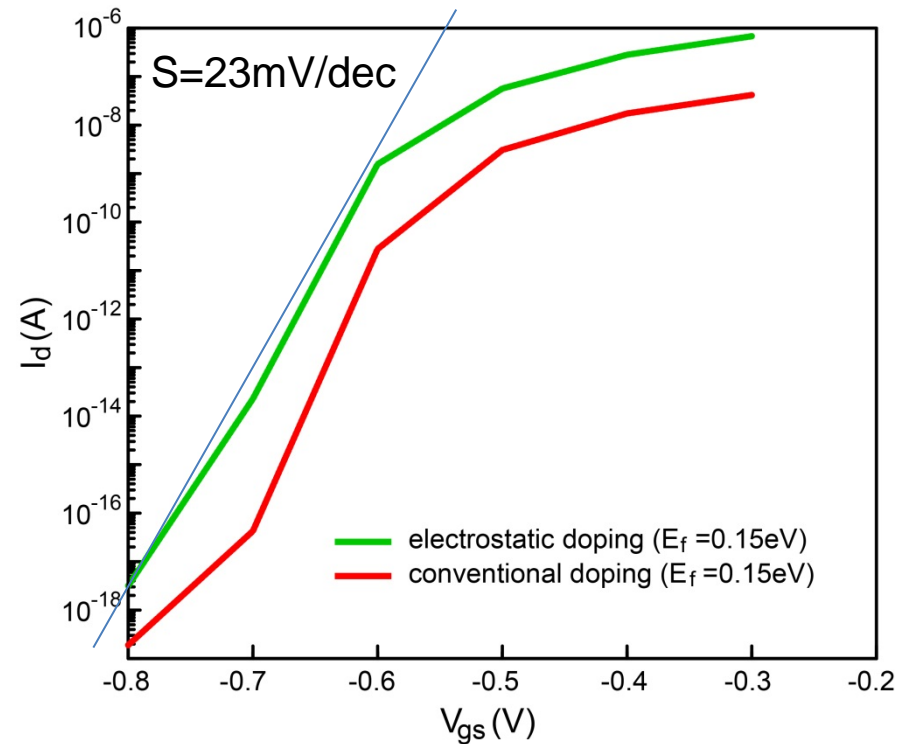
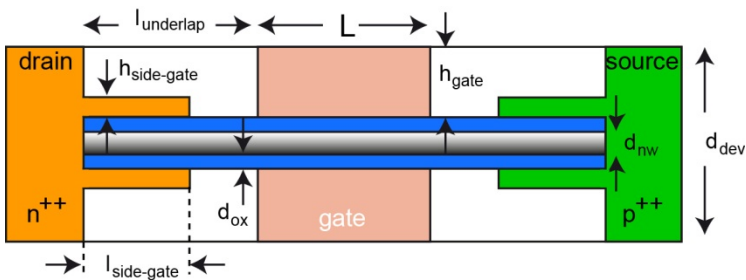
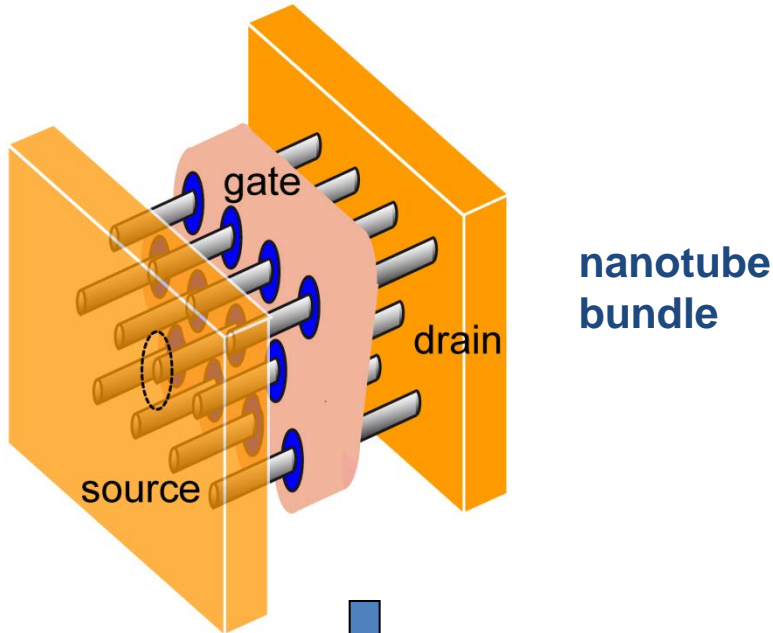
Electrostatic Doping in Graphene



- back-gate voltage characteristics for different coupling strengths
- second peak unobservable if coupling too large

J. Knoch, Z. Chen and J. Appenzeller, IEEE Trans. Nanotechnol., **11**, 513 (2012).

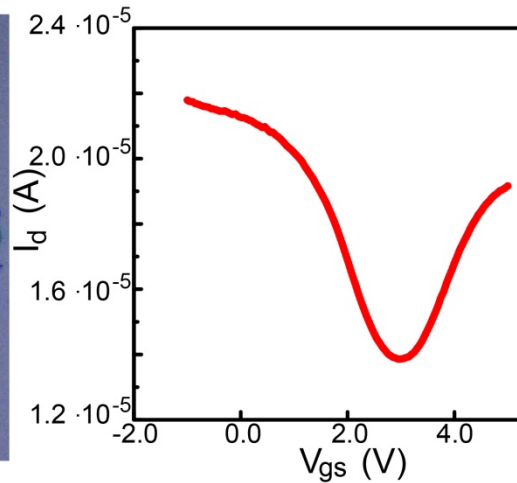
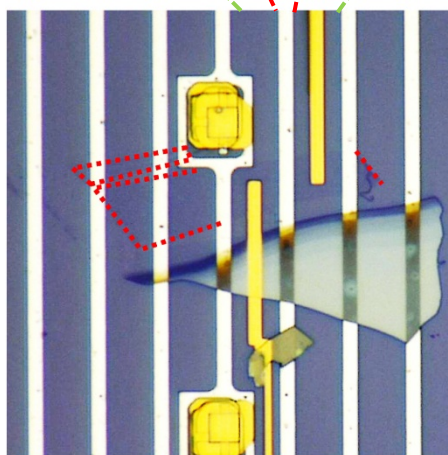
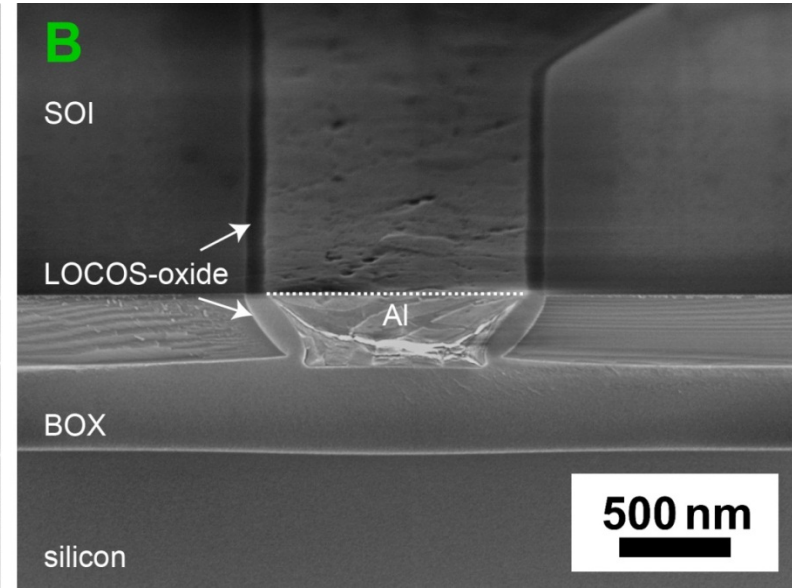
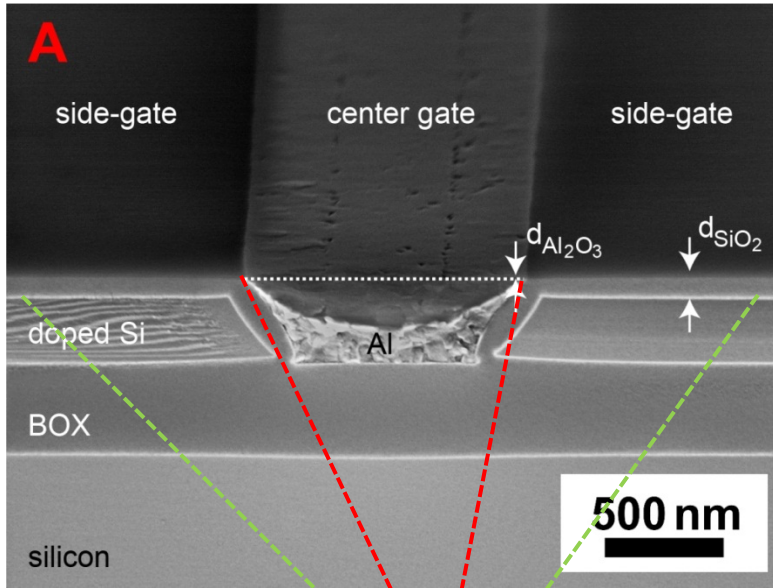
Electrostatic Doping in CNT Tunnel-FETs



- significantly improved on-state due to improved screening
- steep inverse subthreshold slope of 23mV/dec over several orders of magnitude

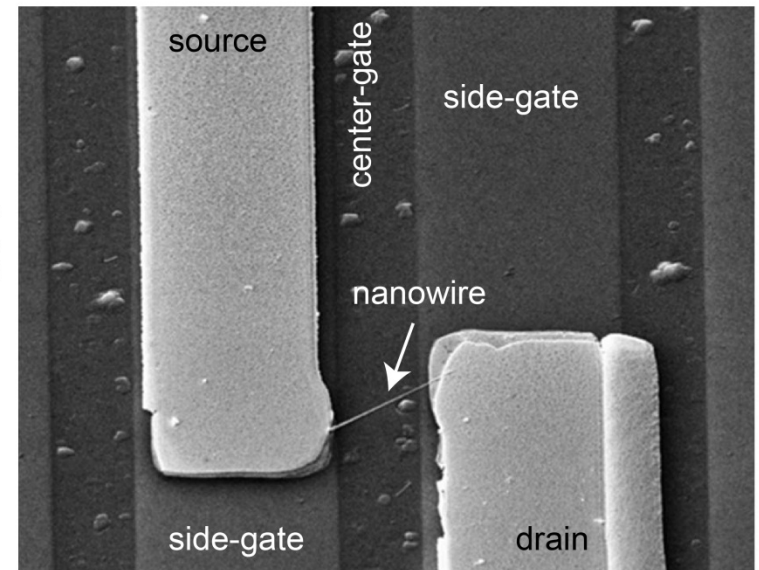
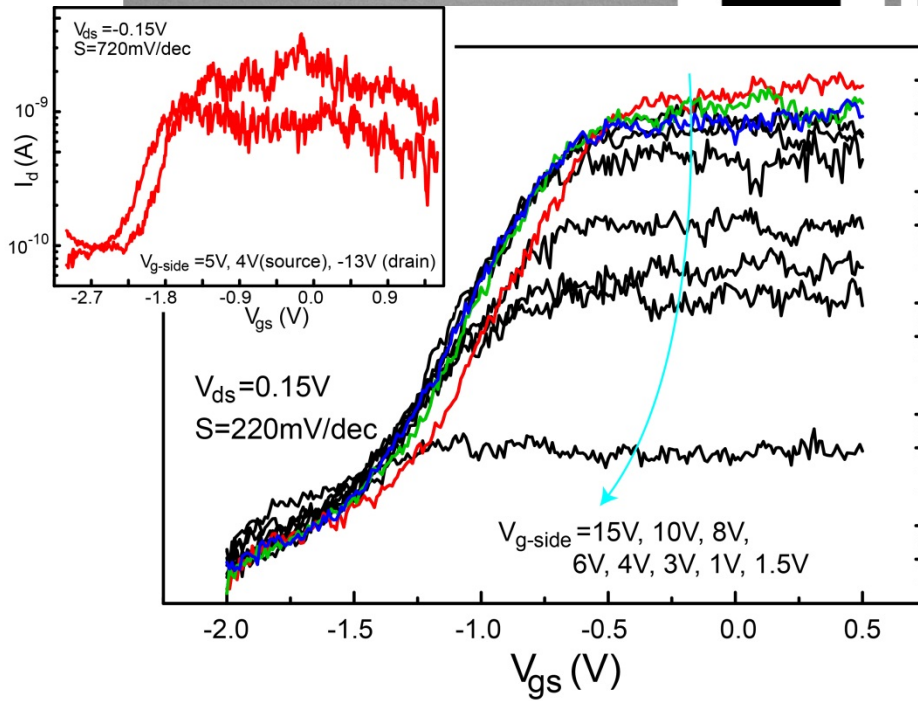
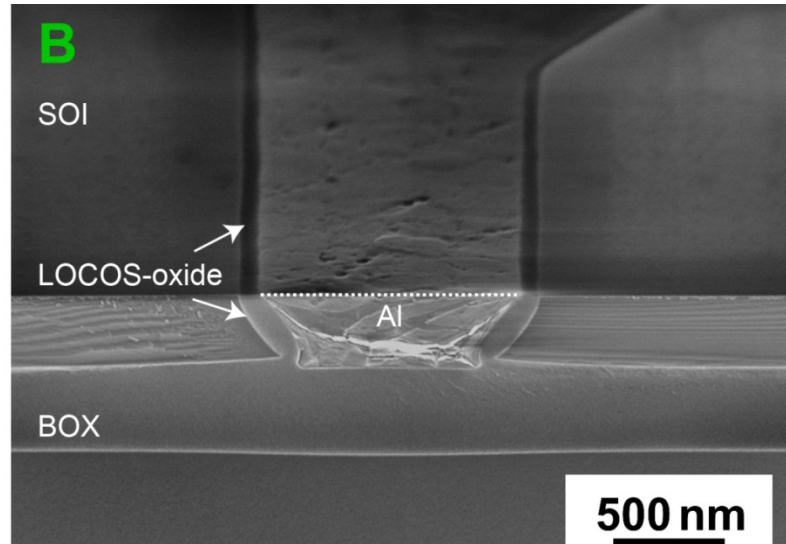
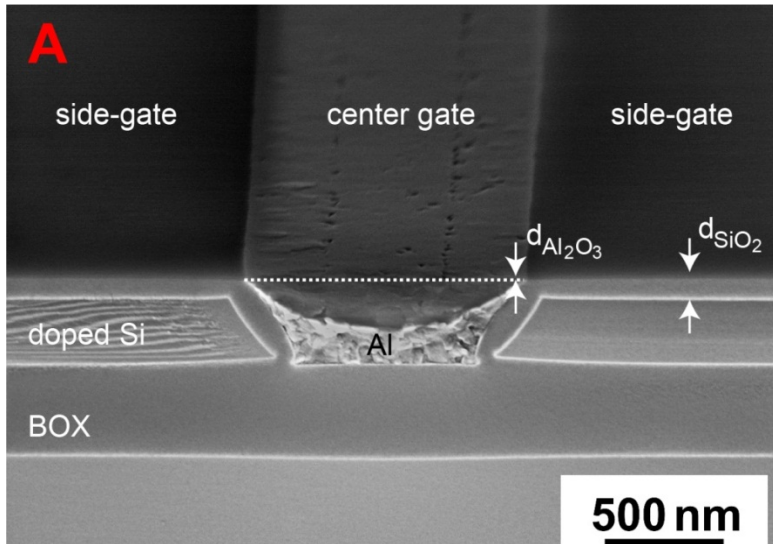
T. Grap and J. Knoch, submitted for publication

Electrostatic Doping

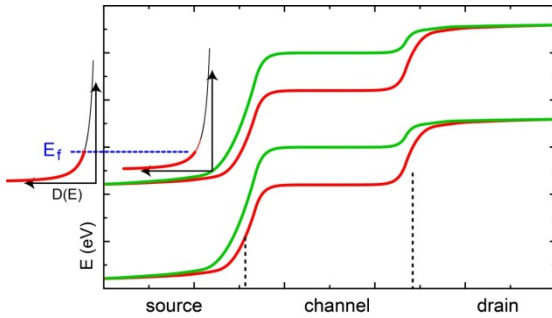


C. Kontis, M. Müller, K. Kallis and J. Knoch, Appl. Optics, **51**, 385 (2012).

Electrostatic Doping

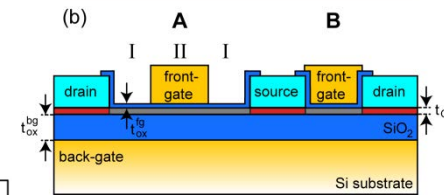
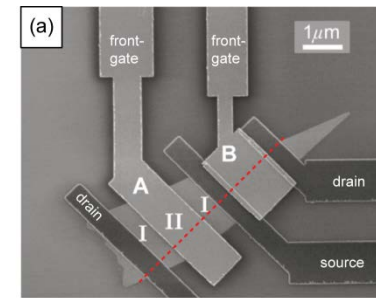
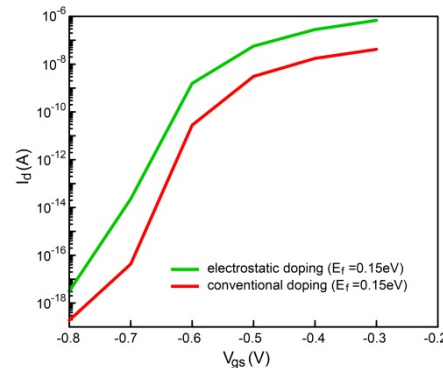
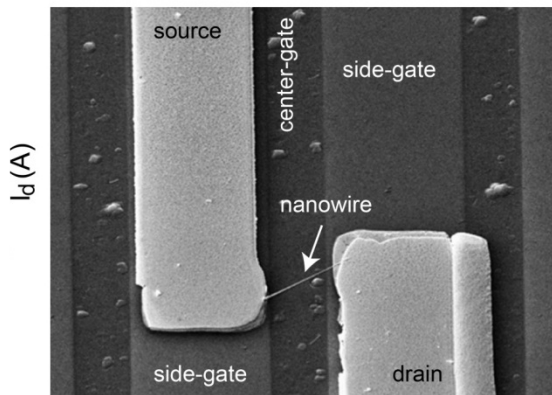


Conclusion



- low density of states detrimental for novel transistor concepts such as tunnel FETs due to insufficient screening

- electrostatic doping avoids issues related to doping *and* adds flexibility for general investigations of carbon based nanostructures



Acknowledgements

- M. Müller – RWTH Aachen and TU Dortmund
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